

AMAT UVision 200S Serial nr T730 Vintage 2007 300mm

Information contained in this presentation is confidential

## AMAT UVision 200S Serial nr T730 Vintage 2007 300mm Location warehouse Nijmegen condition "As is"

Manufacturer: Applied Materials Type: 300mm UVision Serial number: T730 Date of manufacture: 2007

#### The AMAT

Uvision SP 200 is a BF (Bright Field) wafer inspection tool It is designed to inspect pattern wafers, but it can also inspect bare and unpatterned wafers Ligth source: Laser (266 = anm) Tool scans a wafer in a meander path Die to Die " and Cell to Cell " comparison capability Can use reflected --( BrigthField ) and scattered signal (GF = GreyField ) in parallel for detection On pattern wafers capable of detecting defects of 25 nm with 90 % Capture Rate (Data from D&E recipe,







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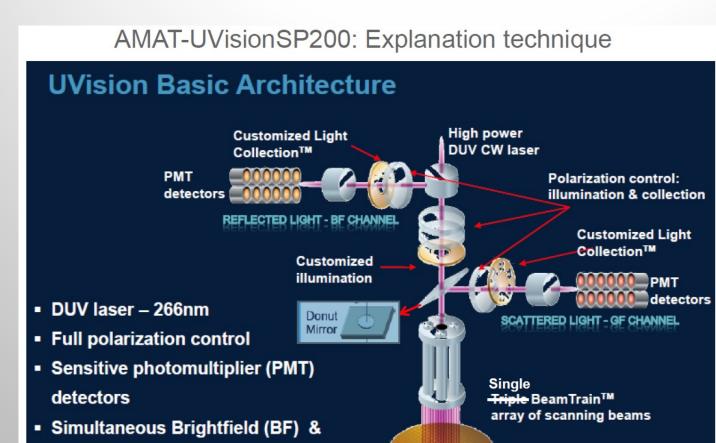


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scattered light – Greyfield (GF)

inspection





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